

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/758,764	YAMAGUCHI ET AL.	
Examiner		Art Unit	Mark Ruthkosky	
		1745	Page 1 of 1	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,807,645	09-1998	Takeuchi et al.	429/231.4
	B	US-			
	C	US-			
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	E	US-			
	F	US-			
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	K	US-			
	L	US-			
	M	US-			

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	N	EP 1,063,713	12-2000	EPO	Bannai	H01M 2/02
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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